



10NK80Z

Preliminary

POWER MOSFET

10A, 800V N-CHANNEL POWER MOSFET

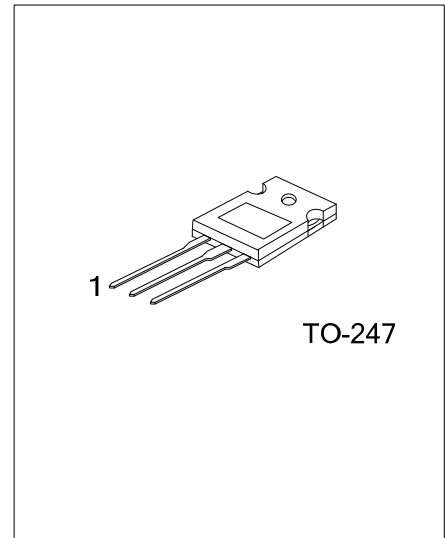
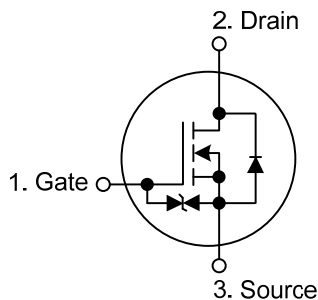
DESCRIPTION

The UTC **10NK80Z** is a silicon N-channel MOSFET, it uses UTC's advanced technology to provide the customers with a minimum on state resistance, high switching speed and low gate charge.

FEATURES

- * $R_{DS(ON)} \leq 1.0 \Omega$ @ $V_{GS}=10V$, $I_D=5.0A$
- * High switching speed
- * Low input capacitance
- * With ESD protection

SYMBOL



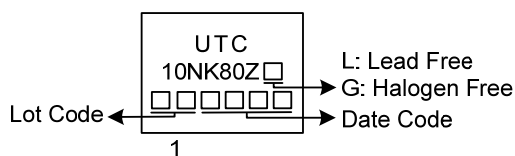
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
10NK80ZL-T47-T	10NK80ZG-T47-T	TO-247	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

10NK80ZG-T47-T (1)Packing Type (2)Package Type (3)Green Package		(1) T: Tube (2) T47: TO-247 (3) G: Halogen Free and Lead Free, L: Lead Free
---	--	--

MARKING



■ **ABSOLUTE MAXIMUM RATING** ($T_C=25^{\circ}\text{C}$ unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DS}	800	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current	DC	I_D	10
	Pulsed (Note 2)	I_{DM}	30
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	1250
Peak Diode Recovery dv/dt (Note 4)	dv/dt	1.1	V/ns
Power Dissipation	P_D	160	W
Junction Temperature	T_J	+150	$^{\circ}\text{C}$
Storage Temperature Range	T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=100\text{mH}$, $I_{AS} = 5.0\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$.

4. $I_{SD} \leq 10\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DS}$, Starting $T_J=25^{\circ}\text{C}$.

■ **THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	50	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	0.78	$^{\circ}\text{C}/\text{W}$

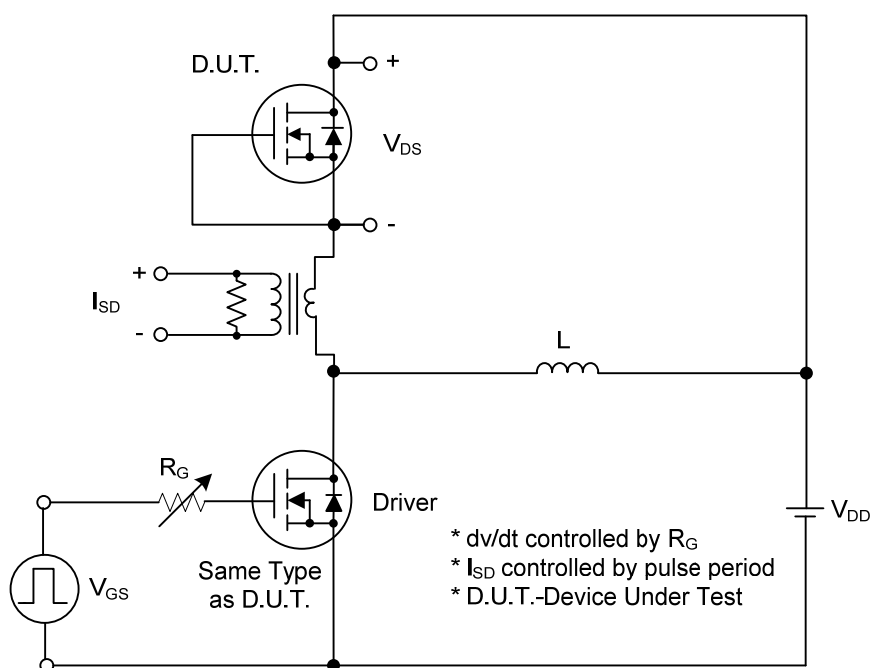
■ **ELECTRICAL CHARACTERISTICS** ($T_A=25^\circ\text{C}$ unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D =250μA	800			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =800V, V _{GS} =0V			10	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} =+20V, V _{DS} =0V			+10	μA
	Reverse		V _{GS} =-20V, V _{DS} =0V			-10	μA
ON CHARACTERISTICS							
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	3.0		5.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =5.0A			1.0	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C _{ISS}	V _{GS} =0V, V _{DS} =50V, f=1.0MHz		2603		pF
Output Capacitance		C _{OSS}			149		pF
Reverse Transfer Capacitance		C _{RSS}			19.1		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q _G	V _{DS} =640V, V _{GS} =10V, I _D =10A (Note 1, 2)		86.5		nC
Gate to Source Charge		Q _{GS}			29.9		nC
Gate to Drain Charge		Q _{GD}			28		nC
Turn-ON Delay Time		t _{D(ON)}	V _{DD} =100V, V _{GS} =10V, I _D =10A, R _G =25Ω (Note 1, 2)		51		ns
Rise Time		t _R			31.4		ns
Turn-OFF Delay Time		t _{D(OFF)}			175		ns
Fall-Time		t _F			60.6		ns
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Continuous Drain-Source Diode Forward Current		I _S				10	A
Maximum Pulsed Drain-Source Diode Forward Current		I _{SM}				30	A
Diode Forward Voltage		V _{SD}	I _F =10A, V _{GS} =0V			1.4	V
Reverse Recovery Time		t _{rr}	I _S =10A, V _{GS} =0V,		773		ns
Reverse Recovery Charge (Note 1)		Q _{rr}	dl _F /dt = 100 A/μs		8.8		uC

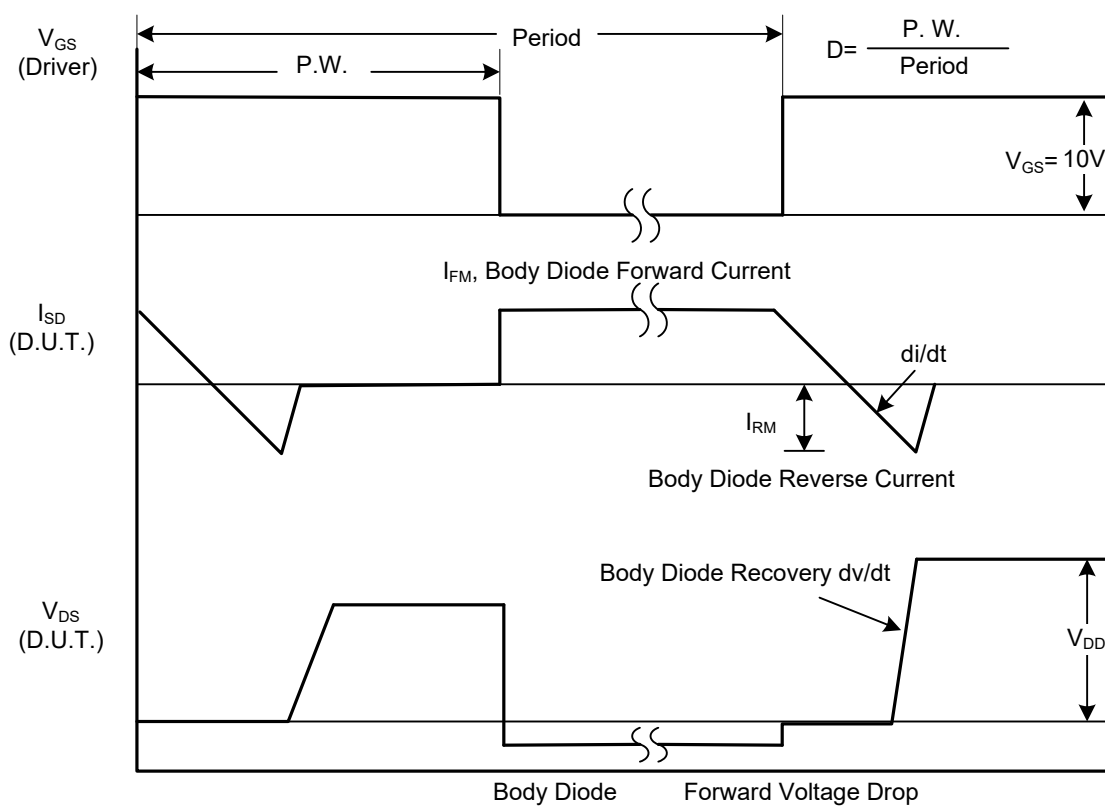
Notes: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

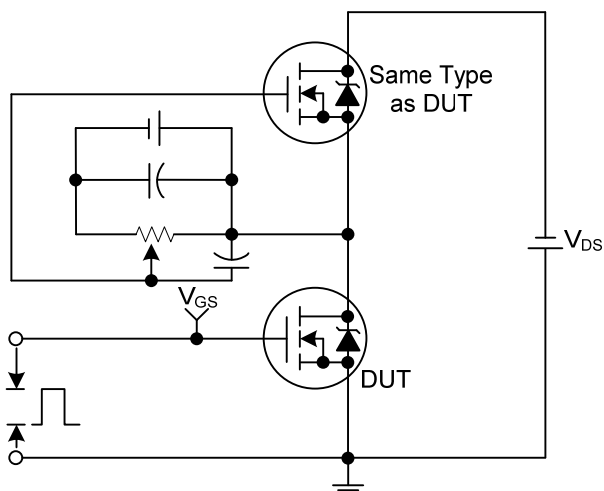


Peak Diode Recovery dv/dt Test Circuit

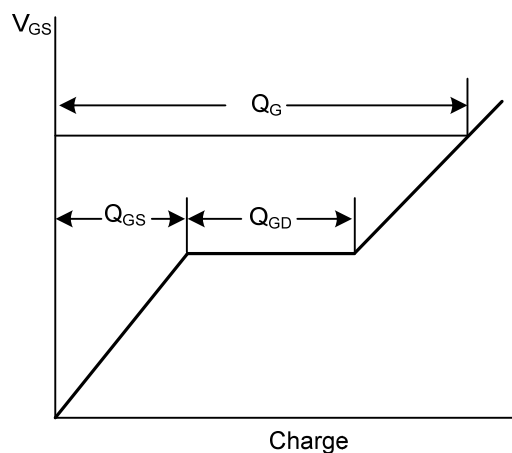


Peak Diode Recovery dv/dt Waveforms

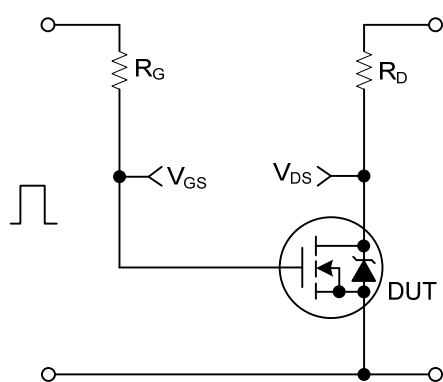
■ TEST CIRCUITS AND WAVEFORMS



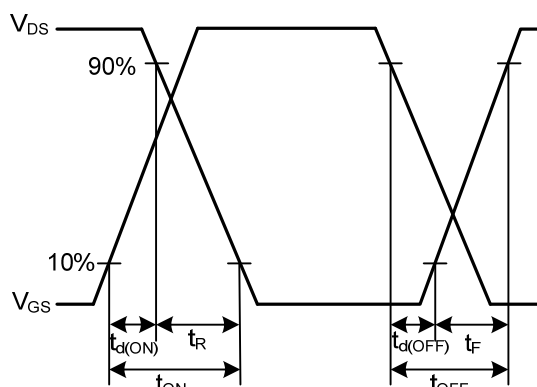
Gate Charge Test Circuit



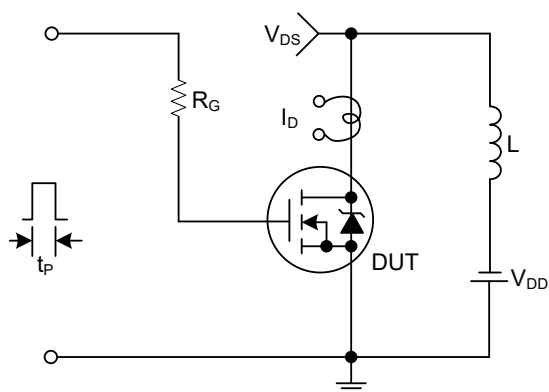
Gate Charge Waveforms



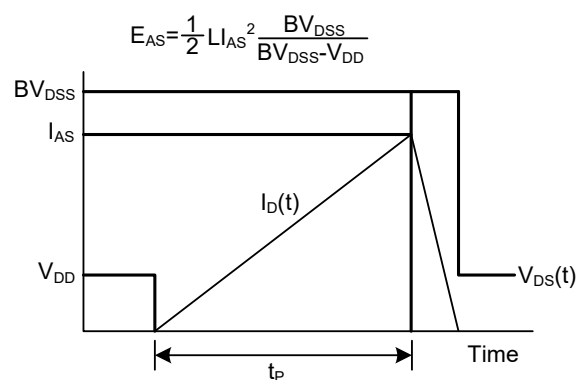
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.